

Attorney Docket No. 1514.1030

## THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:

Ji Yong PARK et al.

Application No.: 10/734,162

Group Art Unit: 2815

Filed: December 15, 2003

Examiner: Landau, Matthew C.

For: THIN FILM TRANSISTOR WITH LDD/OFFSET STRUCTURE

## **INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents PO Box 1450 Alexandria, VA 22313-1450

Sir:

In accordance with the duty of disclosure provisions of 37 CFR § 1.56, there is hereby provided certain information which the Examiner may consider material to the examination of the subject U.S. patent application. It is requested that the Examiner make this information of record if it is deemed material to the examination of the subject application.

1.	E	Enclosures accompanying this Information Disclosure Statement are:					
		1a. 🛛	Form PTO-1449.				
		1b. 🛚	Copy(ies) of IDS citation(s), except for U.S. Patents and U.S. Patent Application publications.				
		1c. 🗌	English language copy of a communication(s) from a foreign Patent Office or a PCT International Search Report.				
		1d. 🗌	English language translation (Abstract Only) attached to non-English language publications as indicated on the attached Form PTO-1449.				
		1e. 🗌	Explanations of Relevancy of References (ATTACHMENT 1(e), hereto) for				
		1f. 🗀	providing a concise explanation of non-English publications.  List of Copending Applications (ATTACHMENT 1(f), hereto).				
		1g. 🔲	List of Additional Submitted Documents (ATTACHMENT 1(g), hereto).				
2.	$\boxtimes$	This Infor	mation Disclosure Statement is filed under 37 CFR § 1.97(b):				
			(Check either Item 2a or 2b or 2c or 2d)				
		2a. 🗌 2b. 🔲	Within three months of the filing date of a national application; Within three months of the date of entry of the national stage as set forth in				
		2c. 🛛	§ 1.491 in an international application.  Before the mailing of a first Office Action on the merits; or				

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	2d. 🗌	Before the mailing of a first Office Action after the filing of a Request for Continued Examination under § 1.114.
3.	specified Action und	mation Disclosure Statement is filed under 37 CFR § 1.97(c) after the period in paragraph 2 above but before the mailing date of any of a Final Office der § 1.113, a Notice of Allowance under § 1.311 or an action that otherwise osecution in the application, AND
		(Check either Item 3a or 3b; Item 3b to be checked if any reference known for more than 3 months)
	3a.	The § 1.97(e) Statement in Item 5 below is applicable; OR The \$180.00 fee set forth in 37 CFR § 1.17(p) is: ☐ enclosed.
		to be charged to Deposit Account No. 503333.
4.	specified	mation Disclosure Statement is filed under 37 CFR § 1.97(d) after the period in paragraph 3 above, but on or before payment of the Issue Fee, AND
	4a.	The § 1.97(e) Statement in Item 5 below is applicable; AND The \$180.00 fee set forth in 37 CFR § 1.17(p) is:  enclosed.
		to be charged to Deposit Account No. 503333.
5.	Statemen	t under § 1.97(e) (applicable if Item 3a or Item 4a is checked) (Check either Item 5a or 5b)
	5a. 🗌	In accordance with 37 CFR § 1.97(e)(1), it is stated that each item of information contained in this Information Disclosure Statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this
	5b. 🗌	Information Disclosure Statement. In accordance with 37 CFR § 1.97(e)(2), it is stated that no item of information contained in this Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart foreign application and, to the knowledge of the person signing the certification after making reasonable inquiry, no item of information contained in this Information Disclosure Statement was known by any individual designated in § 1.56(c) more than three months prior to the filing of this Information Disclosure Statement.
6.	This is a o	continuation/divisional/continuation-in-part application under 37 CFR §
		(Check appropriate Items 6a and/or 6b)
	6a. 🗌	Copies of the publications listed on the attached Form PTO-1449 which were previously cited in prior application Serial No, filed on, and which is relied on for an earlier effective filing date for the subject application under 35 U.S.C. § 120, have been omitted pursuant to 37 CFR § 1.98(d).

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		6b. 🗌	Copies of the publications listed on the attached Form PTO-1449 which were not previously cited in prior application Serial No, filed on, and which is relied on for an earlier effective filing date for the subject application under 35 U.S.C. § 120, are provided herewith.				
7.		This is a	Request for Continued Examination under 37 CFR § 1.114.  (Check either Item 7a or 7b)				
		7a. 🗌 7b. 🗍	The Issue Fee has not been paid. A Petition to Withdraw from issue under 37 CFR § 1.313(c) is filed concurrently herewith or has been granted. A Request for Continued Examination under 37 CFR § 1.114, after payment of the Issue Fee, is proper in accordance with 37 CFR § 1.114(a), respectively.				
8.		This is a Supplemental Information Disclosure Statement.					
			(Check either Item 8a or 8b)				
		8a. 🗌	This Supplemental Information Disclosure Statement under 37 CFR § 1.97(f) supplements the Information Disclosure Statement filed on A bona fide attempt was made to comply with 37 CFR § 1.98, but inadvertent omissions were made. These omissions have been corrected herein. Accordingly, additional time is requested so that this Supplemental IDS can be considered as if properly filed on				
		8b. 🗌	This Supplemental Information Disclosure Statement is timely filed within one (1) month of the Notice under 37 CFR §§ 1.97 and 1.98, mailed				
9.			nce with 37 CFR § 1.98, a concise explanation of what is presently I to be the relevance of each non-English language publication is:				
		. —	(Check appropriate Items 9a, 9b, 9c and/or 9d)				
		9a. 🗌	satisfied for the non-English language publication(s) cited on the enclosed "English language version of the search report or action which indicates the degree of relevance found by the foreign office". (See MPEP § 609, Minimum Requirements for an Information Disclosure Statement, Part A(3): Concise Explanation of Relevance, 8th Ed., Rev. 2)				
		9b.     9c.	set forth in the application. satisfied for the non-English language publication(s) indicated on the attached Form PTO-1449 as having an English language translation (Abstract Only) attached thereto.				
		9d. 🗌	enclosed as Attachment 1(e), hereto.				
10.	b se	e, material earch repo	on is made that the information cited in this Statement is, or is considered to to patentability nor a representation that a search has been made (other than int(s) from a counterpart foreign application or a PCT International Search abmitted herewith). 37 CFR §§ 1.97(g) and (h).				

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11. The Commissioner is authorized to credit any overpayment or charge any additional fee required under 37 CFR § 1.17 for this Information Disclosure Statement to Deposit Account No. 503333.

Respectfully submitted,

Registration No.47,269

STEIN, MCEWEN & BUI, LLP

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FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

Sheet 1 of 1

APPLICATION NO.

1514.1030
FIRST NAMED INVENTOR

Ji Yong PARK et al.

FILING DATE
December 15, 2003

2815

## **U.S. PATENT DOCUMENTS**

*EXAMINER INITIAL	**	DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						

## FOREIGN PATENT DOCUMENTS

	DOCUMENT NO.	DATE	COUNTRY	TRANSLATION YES NO	ABSTRACT
AG					
AH					
Al					

	TRANSL YES	ATION NO		
	AJ	Wang, Mingxiang and Man Wong. "Characterization of an Individual Grain Boundary in Metal-Induced Laterally Crystallized Polycrystalline Silicon Thin-Film Devices." <u>IEEE Transactions on Electron Devices.</u> Vol. 48, No. 8, August 2001, pages 1655-1660.		
	AK	Cho, Hans S. et al. "Sequential Lateral Solidification of Ultra-Thin a-Si Films." Mat. Res. Soc. Symp. Proc. Vol. 621, 2001, pages 1-6.		

EXAMINER	DATE CONSIDERED		
*EXAMINER: Initial if reference considered, whether or not cit			
citation if not in conformance and not considered. Include copy (	of this form with next communication to applicant.		